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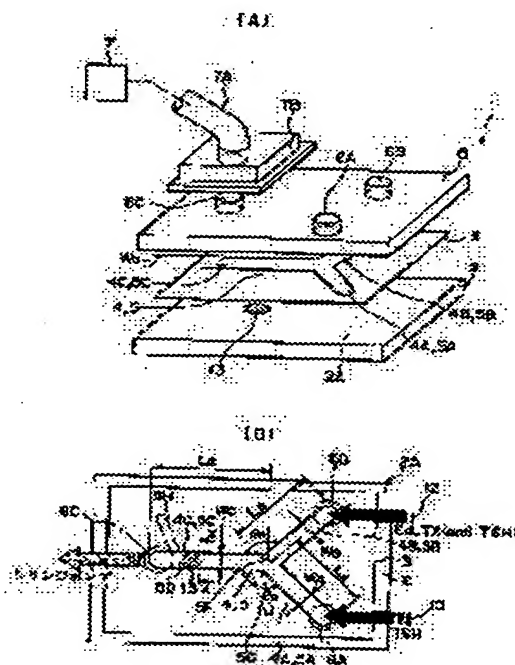
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(54) CHIP FOR MEASURING OBJECT TO BE MEASURED, EQUIPMENT AND METHOD FOR MEASURING OBJECT

(57)Abstract:

PROBLEM TO BE SOLVED: To obtain a chip for measuring an object to be measured, and an equipment and a method for measuring the object in which measurement can be carried out efficiently and accurately and versatility can be enhanced while simplifying the manufacture.

SOLUTION: The chip 1 for measuring an object in a specimen 10 comprises a chip substrate 2, a first groove-like channel 5A for passing the specimen 10 made in the chip substrate 2, a second groove-like channel 5B made in the chip substrate 2 in order to pass a labeling substance 12 having a first substance bonding specifically to the object being measured, a groove-like reaction channel 5 made in the chip substrate 2 by collecting the first channel 5A and the second channel 5B, and a reaction site 5D provided in the reaction channel 5 and fixed with a second substance 13 bonding specifically to the object being measured.



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